October 2008

OFET[™]



FQB8N60CF 600V N-Channel MOSFET

Features

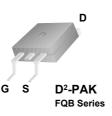
- 6.26A, 600V, $R_{DS(on)}$ = 1.5 Ω @V_{GS} = 10 V
- Low gate charge (typical 28nC)
- Low Crss (typical 12pF)
- · Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS Compliant

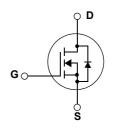


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter	FQB8N60CF	Units	
V _{DSS}	Drain-Source Voltage	600	V	
I _D	Drain Current - Continuous ($T_C = 25^{\circ}C$)	6.26	А	
	- Continuous (T _C = 100°C)	3.96	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	25	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	160	mJ
I _{AR}	Avalanche Current	(Note 1)	6.26	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	14.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P _D	Power Dissipation (T _C = 25°C)		147	W
	- Derate above 25°C	1.18	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes 1/8" from case for 5 seconds	300	°C	

Thermal Characteristics

Symbol	Parameter	FQB8N60CF	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case	0.85	°C/W
R_{\thetaJA}	Thermal Resistance, Junction-to-Ambient*	40	°C/W
R_{\thetaJA}	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

* When mounted on the minimum pad size recommended (PCB Mount)

FQB8N60
ĥ
600V
N-Ch
annel
SOW
Ë

Device Marking Device Packa		Packag	ge Reel Size Tap		be Width		Quantity			
FQB8N	·		D2-PAK	K 330mm			24mm		800	
Electric	al Chai	racteristics T _c	= 25°C unless other	wise noted						
Symbol	Parameter		Test Conditions		Min	Тур	Max	Units		
Off Charac	teristics									
BV _{DSS}	Drain-Source Breakdown Voltage		V_{GS} = 0 V, I _D = 250 µA			600			V	
∆BV _{DSS} / ∆T _J	Breakdown Voltage Temperature Coefficient		I_D = 250 µA, Referenced to 25°C				0.7		V/°C	
I _{DSS}	Zero Gate	ro Gate Voltage Drain Current		V _{DS} = 600 V, V _{GS} = 0 V					10	μA
			V _{DS} = 480 V, T _C = 125°C					100	μA	
I _{GSSF}	Gate-Bod	Gate-Body Leakage Current, Forward V _{GS} = 30			= 0 V				100	nA
I _{GSSR}	Gate-Bod	Gate-Body Leakage Current, Reverse		V _{GS} = -30 V, V _{DS} = 0 V					-100	nA
On Charact	eristics									
V _{GS(th)}	Gate Threshold Voltage			$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			2.0		4.0	V
R _{DS(on)}	Static Dra	Static Drain-Source On-Resistance		V _{GS} = 10 V, I _D = 3.13A				1.25	1.5	Ω
9 _{FS}	Forward Transconductance			V _{DS} = 40 V, I _D = 3.13 A (Note 4)				8.7		S
Dynamic Cl	aracteristi	cs								
C _{iss}	Input Cap	pacitance	V _{DS} = 25 V, V _{GS} = 0 V,				965	1255	pF	
C _{oss}	Output Ca	Output Capacitance		f = 1.0 MHz				105	135	pF
C _{rss}	Reverse Transfer Capacitance						12	16	pF	
Switching C	haracterist	tics								
t _{d(on)}	Turn-On Delay Time			V _{DD} = 300 V, I _D = 6.26A,				16.5	45	ns
t _r	Turn-On I	Rise Time		R _G = 25 Ω				60.5	130	ns
t _{d(off)}	Turn-Off I	Delay Time						81	170	ns
t _f	Turn-Off I	Fall Time			(N	ote 4, 5)		64.5	140	ns
Qg	Total Gate	e Charge		V _{DS} = 480 V, I _D =	6.26A,			28	36	nC
Q _{gs}	Gate-Sou	rce Charge		V _{GS} = 10 V				4.5		nC
Q _{gd}	Gate-Drain Charge (Note			ote 4, 5)		12		nC		
Drain-Sourc	e Diode C	haracteristics and Ma	ximum Ratings							
I _S	Maximum Continuous Drain-Source Diode For			rward Current					6.26	Α
I _{SM}	Maximum	Pulsed Drain-Source	Diode Forward	d Current					25	А
V _{SD}	Drain-Sou	urce Diode Forward V	oltage	V_{GS} = 0 V, I _S = 6.26 A					1.4	V
t _{rr}	Reverse I	Recovery Time		$V_{GS} = 0 V, I_{S} = 6.$				82		ns
Q _{rr}	Reverse I	Recovery Charge		$dI_{F} / dt = 100 \text{ A}/\mu \text{s}$ (Note 4)		(Note 4)		242		nC

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

2. L = 7.3mH, I_{AS} = 6.26A, V_DD = 50V, R_G = 25 $\Omega,$ Starting $\mbox{ T}_{J}$ = 25°C

3. I_{SD} \leq 6.26A, di/dt \leq 200A/\mu s, V_{DD} \leq BV_{DSS,} Starting $\ T_{J}$ = 25°C

4. Pulse Test : Pulse width $\leq 300 \mu s, \, Duty \, cycle \leq 2\%$

5. Essentially independent of operating temperature

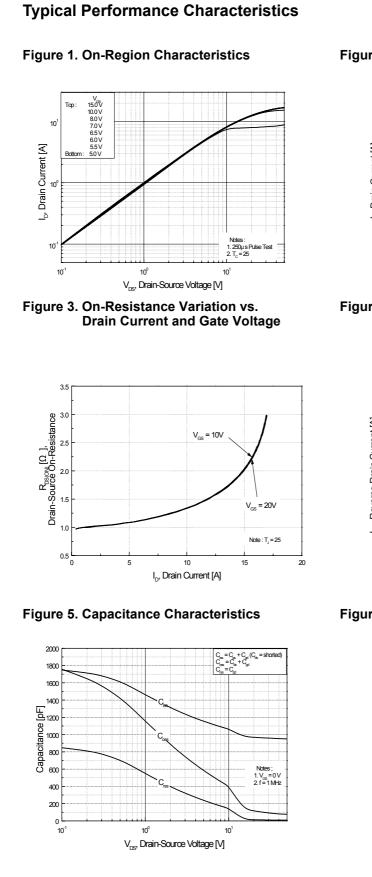
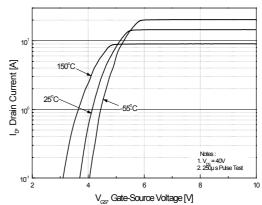
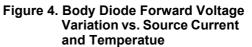


Figure 2. Transfer Characteristics





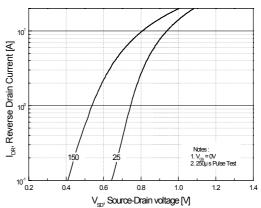
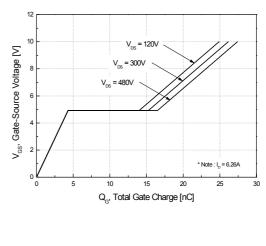
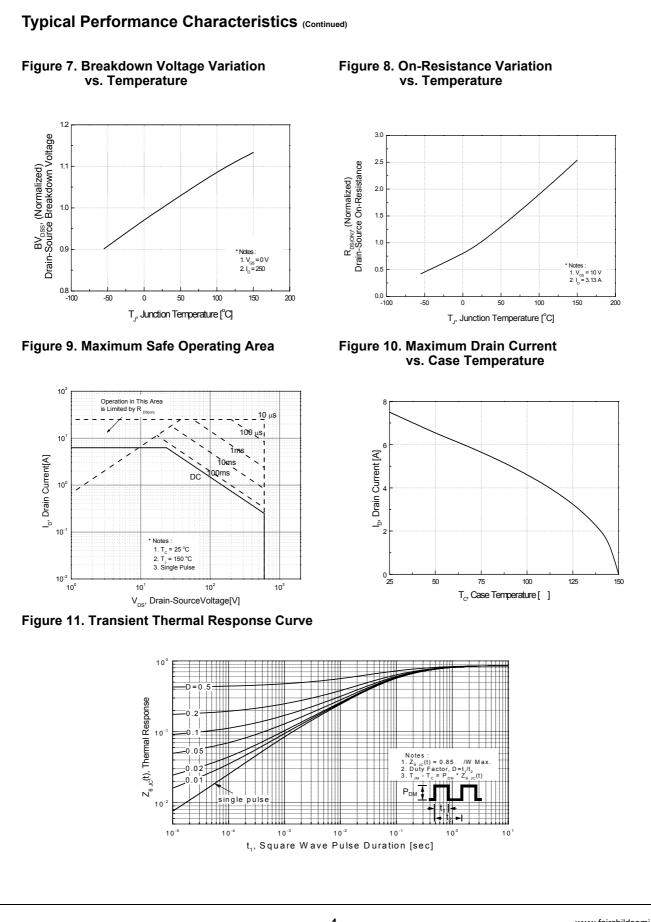
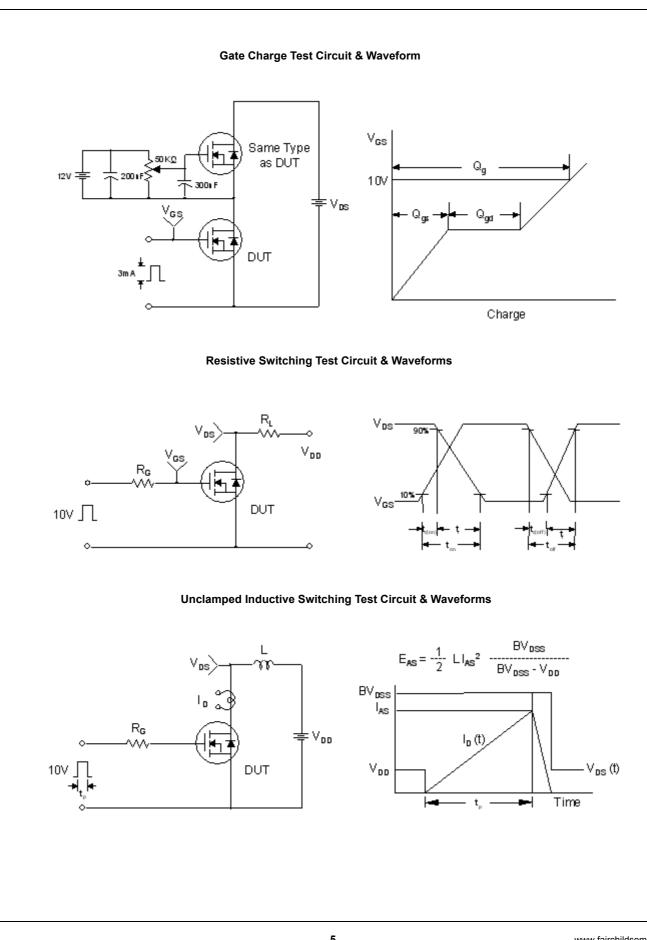
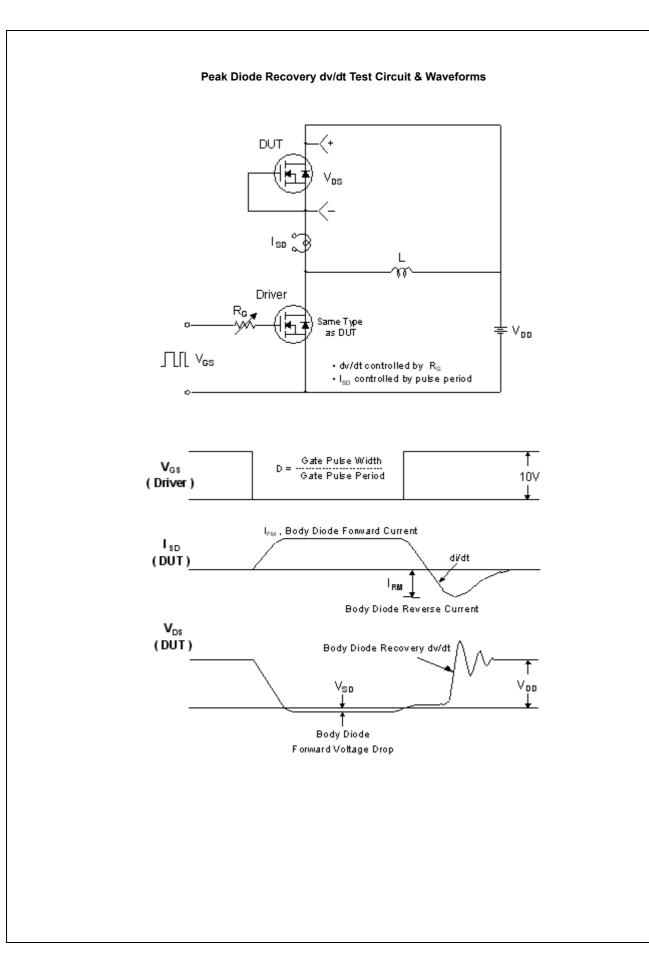


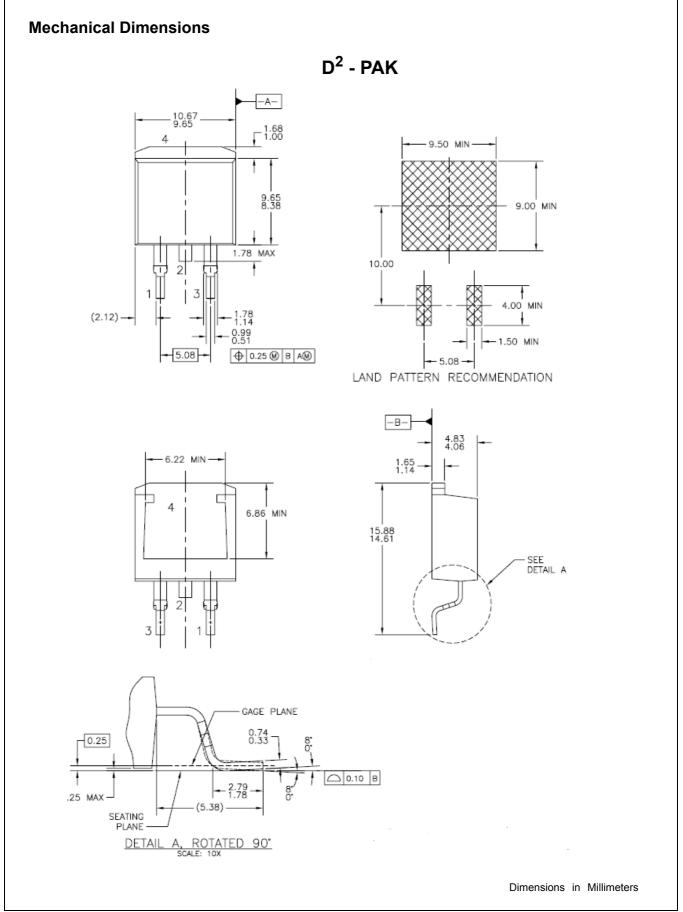
Figure 6. Gate Charge Characteristics













SEMICONDUCTOR

TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

FRFET® Build it Now™ Programmable Active Droop™ Global Power ResourceSM CorePLUS™ QFET CorePOWER™ Green FPS™ QS™ Green FPS™ e-Series™ CROSSVOLT™ Quiet Series™ CTI ™ GTO™ RapidConfigure™ IntelliMAX™ Current Transfer Logic™ EcoSPARK[®] ISOPI ANARTM EfficentMax™ MegaBuck[™] Saving our world, 1mW /W /kW at a time™ EZSWITCH™ * MICROCOUPLER™ SmartMax™ SMART START™ SPM[®] MicroFET™ MicroPak™ STEALTH™ MillerDrive™ MotionMax™ SuperFET™ Fairchild® Motion-SPM™ SuperSOT™-3 Fairchild Semiconductor® OPTOLOGIC[®] SuperSOT™-6 FACT Quiet Series™ OPTOPLANAR[®] SuperSOT™-8 FACT® SupreMOS™ FAST® SyncFET™ FastvCore™ PDP SPM™ FlashWriter[®] * Power-SPM™ **FPS™** The Power Franchise[®] PowerTrench[®] F-PFS™ PowerXS™

* EZSWITCH™ and FlashWriter[®] are trademarks of System General Corporation, used under license by Fairchild Semiconductor

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Farichild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Farichild strongly encourages customers to purchase Farichild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Farichild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Farichild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition				
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.				
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.				
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.				
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.				

Uwer p we franchise

TinyBoost™

TinyBuck™

TinyLogic[®]

TINYOPTO™

TinyPower™

TinyPWM™

TinyWire™

μSerDes™

Ultra FRFET™

UHC®

VCX™

XS™

UniFET™

VisualMax™